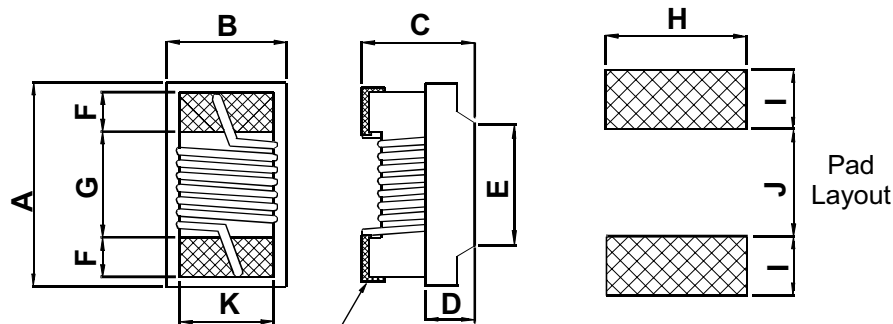


Wire-Wound Chip Inductor 1008 (252018) Series

Shape & Dimension



Terminal wraparound:
Approx. 0.018/0.45 both ends

	A		B		C		D Ref.	E Ref.	F	G	H	I	J	K
	Max.	Ref.	Max.	Ref.	Max.	Ref.								
Inch	0.115	0.103	0.110	0.095	0.080	0.072	0.025	0.065	0.020	0.060	0.100	0.040	0.050	0.080
mm	2.92	2.60	2.79	2.40	2.03	1.82	0.65	1.65	0.51	1.52	2.54	1.02	1.27	2.03

Parts/Reel: 7" 2,000 PCS

Tape Width: 8mm

Specification For Approval

Wire-Wound Chip Inductor 1008 (252018) Series

PART NUMBER	INDUCTANCE uH	TEST FREQUENCY (M Hz)	Q MIN	SRF MIN GHz	RDC MAX Ohms	IDC Max mA
BCCWH-252018-5N6J	0.0056	50	50@1500MHz	4000	0.15	1000
BCCWH-252018-10N_	0.01	50	50@500MHz	4100	0.08	1000
BCCWH-252018-12N_	0.012	50	50@500MHz	3300	0.09	1000
BCCWH-252018-15N_	0.015	50	50@500MHz	2500	0.11	1000
BCCWH-252018-18N_	0.018	50	50@350MHz	2400	0.12	1000
BCCWH-252018-22N_	0.022	50	55@350MHz	2400	0.12	1000
BCCWH-252018-24N_	0.024	50	55@350MHz	1900	0.12	1000
BCCWH-252018-27N_	0.027	50	55@350MHz	1600	0.13	1000
BCCWH-252018-33N_	0.033	50	60@350MHz	1600	0.14	1000
BCCWH-252018-39N_	0.039	50	60@350MHz	1500	0.15	1000
BCCWH-252018-47N_	0.047	50	65@350MHz	1500	0.16	1000
BCCWH-252018-56N_	0.056	50	65@350MHz	1300	0.18	1000
BCCWH-252018-68N_	0.068	50	65@350MHz	1300	0.2	1000
BCCWH-252018-82N_	0.082	50	60@350MHz	1000	0.22	1000
BCCWH-252018-R10_	0.1	25	60@350MHz	1000	0.56	650
BCCWH-252018-R12_	0.12	25	60@350MHz	950	0.63	650
BCCWH-252018-R15_	0.15	25	45@100MHz	850	0.7	580
BCCWH-252018-R18_	0.18	25	45@100MHz	750	0.77	620
BCCWH-252018-R22_	0.22	25	45@100MHz	700	0.84	500
BCCWH-252018-R24_	0.24	25	45@100MHz	650	0.88	500
BCCWH-252018-R27_	0.27	25	45@100MHz	600	0.91	500
BCCWH-252018-R30_	0.3	25	45@100MHz	585	1	450
BCCWH-252018-R33_	0.33	25	45@100MHz	570	1.05	450
BCCWH-252018-R36_	0.36	25	45@100MHz	530	1.1	470
BCCWH-252018-R39_	0.39	25	45@100MHz	500	1.12	470
BCCWH-252018-R43_	0.43	25	45@100MHz	480	1.15	470
BCCWH-252018-R47_	0.47	25	45@100MHz	450	1.19	470
BCCWH-252018-R56_	0.56	25	45@100MHz	415	1.33	400
BCCWH-252018-R62_	0.62	25	45@100MHz	375	1.4	300
BCCWH-252018-R68_	0.68	25	45@100MHz	375	1.47	400
BCCWH-252018-R75_	0.75	25	45@100MHz	360	1.54	360
BCCWH-252018-R82_	0.82	25	45@100MHz	350	1.61	400
BCCWH-252018-R91_	0.91	25	35@50MHz	320	1.68	380
BCCWH-252018-1R0_	1	25	35@50MHz	290	1.75	370
BCCWH-252018-1R2_	1.2	7.9	35@50MHz	250	2	310
BCCWH-252018-1R5_	1.5	7.9	28@50MHz	200	2.3	330
BCCWH-252018-1R8_	1.8	7.9	28@50MHz	160	2.6	300
BCCWH-252018-2R2_	2.2	7.9	28@50MHz	160	2.8	280
BCCWH-252018-2R7_	2.7	7.9	22@25MHz	140	3.2	290
BCCWH-252018-3R3_	3.3	7.9	22@25MHz	110	3.4	290
BCCWH-252018-3R9_	3.9	7.9	20@25MHz	100	3.6	260

Wire-Wound Chip Inductor 1008 (252018) Series

BCCWH-252018-4R7_	4.7	7.9	20@25MHz	90	4	260
BCCWH-252018-5R6_	5.6	7.9	16@7.96MHz	20	4	240
BCCWH-252018-6R8_	6.8	7.9	15@7.96MHz	40	4.9	200
BCCWH-252018-8R2_	8.2	7.9	15@7.96MHz	25	6	170
BCCWH-252018-100_	10	2.52	15@7.96MHz	20	9	150
BCCWH-252018-120_	12	2.52	15@7.96MHz	18	10.51	130
BCCWH-252018-150_	15	2.52	15@7.96MHz	15	11.51	120

PERCENT TOLERANCE: %10,%5,%2

Wire-Wound Chip Inductor 1008 (252018) Series

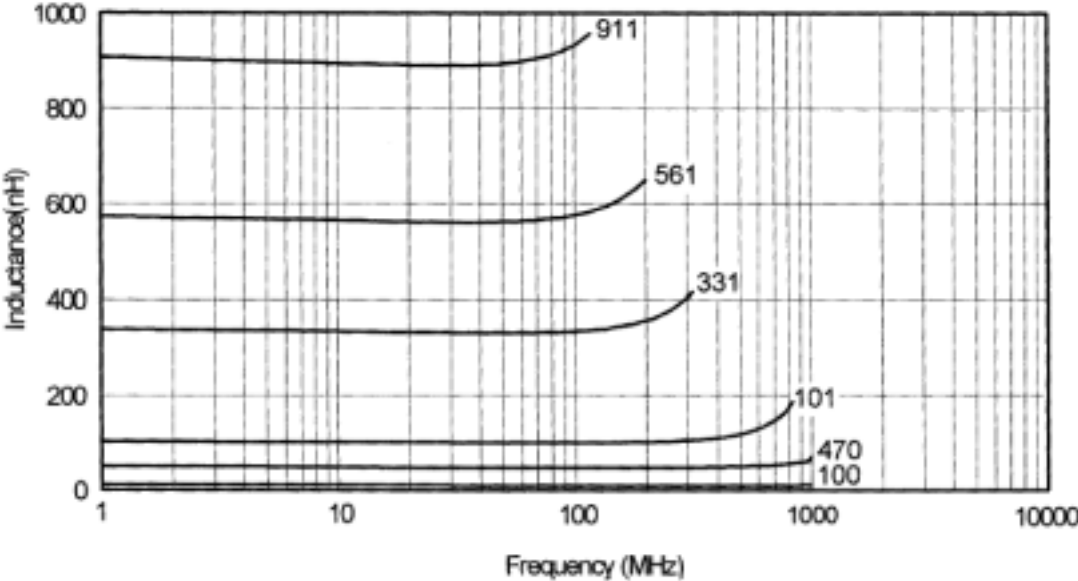
Q vs F & L vs F Curve

WIRE-WOUND CHIP INDUCTOR

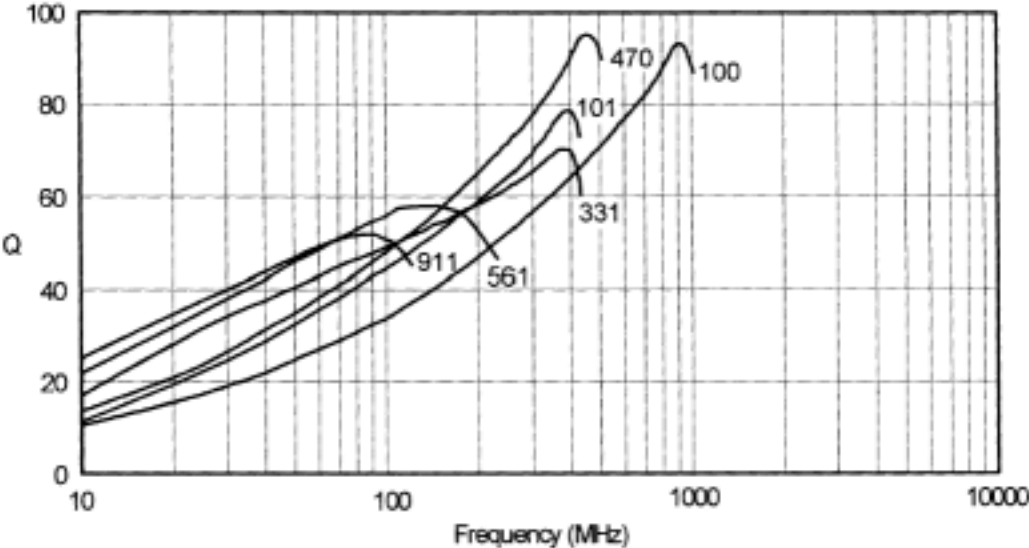


1008CS Series (2520)

TYPICAL L vs FREQUENCY



TYPICAL Q vs FREQUENCY



Wire-Wound Chip Inductor 1008 (252018) Series

Reliability Test Condition

TEST ITEMS	SPECIFICATIONS	TEST CONDITIONS / TEST METHODS
*ELECTRICAL PERFORMANCE TEST		
INDUCTANCE	REFER TO STANDARD ELECTRICAL CHARACTERISTIC LIST	HP 4291B
Q		HP 4291B
SRF		HP 8753D
DC RESISTANCE R _{DC}		Micro-Ohmmeter (GOM-801G)
RATED CURRENT I _{DC}		APPLIED THE CURRENT TO COILS, THE INDUCTANCE CHANGE SHOULD BE LESS THAN 10% TO INITIAL VALUE
OVER LOAD TEST	AFTER TEST, INDUCTORS SHALL BE NO EVIDENCE OF ELECTRICAL AND MECHANICAL DAMAGE	APPLIED 2 TIMES OF RATED ALLOWED DC CURRENT TO INDUCTOR FOR A PERIOD OF 5 MINUTE
WITHSTANDING VOITAGE TEST	1.AFTER TEST, INDUCTORS SHALL BE NO EVIDENCE OF ELECTRICAL AND MECHANICAL DAMAGE	AC VOLTAGE OF 500 VAC APPLIED BETWEEN INDLUICTORS TERMINAL AND CASE FOR 1 MINUTE
INSULATION RESISTANCE TEST	1000 MOHM MIN.	100 VDC APPLIED BETWEEN INDUCTOR TERMINAL AND CASE
*MECHANICAL PERFORMANCE TEST		
VIBARATION TEST (LOW FREQUENCY)	1.INDUCTORS SHOULD HAVE NO EVIDENCE OF ELECTRICAL AND MECHANICAL DAMAGE 2.INDUCTANCE SHOULD NOT CHANGE MORE THAN±5% 3.Q SHOULD NOT CHANGE MORE THAN±10%	1. AMPLITUDE: 1.5m/m 2. FREQUENCY: 10-55-10 Hz(1min) 3. DIRECTION: X, Y, Z 4. DURATION: 2 HRS/X, Y, Z
RESISTANCE TO SOLDERING TEST		INDUCTORS SHOULD BE REF.LOW TO A .PC BOARD. USING 63Sn/37Pb SOLDER PASTE.SOLDER PROCESS SHOULD BE 230 FOR 20±2 SECONDS AND 260 FOR 5±2 SECONDS.
COMPONENT ADHESIONN (PUSH TEST)	1 lbs. FOR 0402 2 lbs. FOR 0603 4 lbs. FOR THE REST	THE DEVICE SHOULD BE REF.LOW SOLDERED (232 ±5 FOR 10 SECONDS) TO A TINNED COPPER SUBSTRATE. A DYNAMETER FORCE GAUGE SHOULD BE APPLIED TO THE SIDE OF THE COMPONENT. THE DEVICE MUST WITHSTAND A MINIMUM FORCE OF 2 OR 4 POUNDS WITHOUT A FAILURE OF THE TERMINATION ATTACHED TO COMPONENT.
DROP TEST	AFTER TEST ,THE CHIP INDUCTOR DON'T FELL OR BROKE ON THE P.C BOARD.	DROP 1 TIME FOR EACH FACE AND 1 TIME FOR EACH CORNER.TOTAL DROP 10 TIMES. DROP HEIGHT :100 CM DROP WEIGHT :125 g
SOLDERABILITY TEST	THE TERMINAL SHOULD AT LEAST BE 90% COVERED WITH SOLDER	AFTER FLUXING(ALPHA 100 OR EQUIV), INDUCTOR SHALL BE DIPPED IN A MELTED SOLDER BATH AT 232 ±5 FOR 5 SECONDS.

Specification For Approval

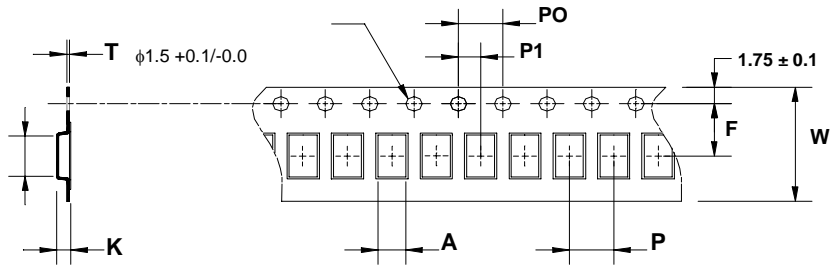
Wire-Wound Chip Inductor 1008 (252018) Series

SOLDERABILITY TEST	THE TERMINAL SHOULD HAVE AT LEAST 90% COVERED WITH SOLDER	AFTER FLUXING (ALPHA 100 OR EQUIV), INDUCTOR SHALL BE DIPPED IN A MELTED SOLDER BATH AT 232 ±5 FOR 5 SECONDS.
RESISTANCE TO SOLVENT TEST	THERE SHALL BE NO CASE OF DEFORMATION CHANGE IN APPEARANCE OR OBLITERATION OF MARKING.	MIL-STD202F, METHOD 215D
*CLIMATIC TEST		
TEMPERATURE CHARACTERISTIC	1.INDUCTORSSHAL HAVE NO EVIDENCE OF ELECTRICAL AND MECHANICAL DAMAGE 2..INDUCTANCE SHALL NOT CHANGE MORE THAN ±10% 3. SHALL NOT CHANGE MORE THAN ±20%	-40 ~ +125
HUMIDITY TEST		1. TEMP : 40 ± 2 2. R.H. : 90 – 95% 3. TIME : 96 ±2 HOURS
LOW TEMPERATURE STORAGE TEST		1. TEMP : -40 ±2 2. TIME : 48 ±2 HOURS 3.INDUCTORS ARE TO BE TESTED AFTER 1HOUR AT ROOM TEMPERATURE.
THERMAL SHOCK TEST		<p style="text-align: center;">TOTAL : 5 CYCLES</p>
HIGH TEMPERATURE STORAGE TEST		1. TEMP : 125 ± 2 2. TIME : 48 ± 2 HOURS 3.INDUCTORS ARE TO BE TESTED AFTER 1HOUR AT ROOM TEMPERATURE.
HIGH TEMPERATURE LOAD LIFE TEST		1. TEMP : 85 ± 2 2. TIME : 1000 ± 12 HOURS 3. LOAD : ALLOWED DC CURRENT
HUMIDITY LOAD LIFE	1. TEMP : 40 ± 2 2. R.H. : 90 – 95% 3. TIME : 1000 ± 12 HOURS 4. LOAD : ALLOWED DC CURRENT	
NOTE : UNLESS OTHERWISE SPECIFIED, ALLOW THE SPECIMEN TO STAND AT ROOM TEMPERATURE FOR 1 HOUR OR MORE BUT NOT MORE THAN 2 HOURS, MEASURE THE ELECTRICAL AND MECHANICAL PERFORMANCES.		

Wire-Wound Chip Inductor 1008 (252018) Series

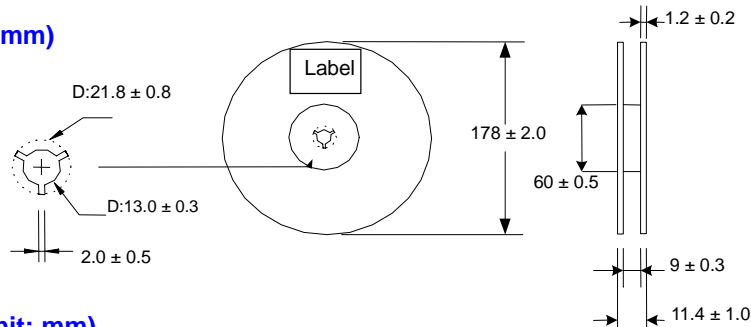
Package Specification.

Tape Dimensions (Unit:mm)

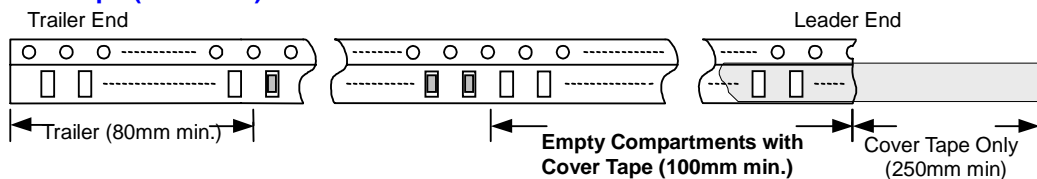


		Tape Dimensions (mm)									Parts (pcs)
		A	B	K	T	F	P	P0	P1	W	7"
Ceramic	252018	2.70	2.80	2.00	0.23	3.5	4	4	2	8	2000
	201209	1.85	2.30	1.45	0.23	3.5	4	4	2	8	2000
	160808	1.12	1.85	0.96	0.23	3.5	4	4	2	8	4000
	100505	0.71	1.16	0.65	0.23	3.5	2	4	0	8	4000
	1008CT	2.70	2.80	1.50	0.23	3.5	4	4	2	8	2000
	0805CT	1.80	2.30	0.90	0.23	3.5	4	4	2	8	2000
	1008CQ	2.70	2.80	2.00	0.23	3.5	4	4	2	8	2000
	0805CQ	1.85	2.30	1.45	0.23	3.5	4	4	2	8	2000
	0603CC	1.12	1.85	0.96	0.23	3.5	4	4	2	8	4000
Ferrite	1812MS	4.90	3.61	3.51	0.23	5.5	8	4	2	12	500
	1210MS	3.71	2.84	2.57	0.23	3.5	4	4	2	8	1000
	1210CS	3.71	2.80	2.50	0.23	3.5	4	4	2	8	1000
	1210HS	3.71	2.80	2.50	0.23	3.5	4	4	2	8	1000
	1008CS	2.70	2.80	2.33	0.23	3.5	4	4	2	8	2000
	1008HS	2.70	2.80	2.00	0.23	3.5	4	4	2	8	2000
	0805CS	1.85	2.30	1.45	0.23	3.5	4	4	2	8	2000

Reel Dimensions (Unit: mm)



Leader / Trailer Tape (Unit: mm)



Peel-off Force

Peel-off force should be in the range of 0.1~0.7N at a peel-off speed of 300±10 mm/min

